FAIRCHILD SEMICONDUCTOR™

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74F544
Octal Registered Transceiver

General Description

The 74F544 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow. The A outputs are guaranteed to sink 24 mA while the B outputs are rated for 64 mA. The 74F544 inverts data in both directions.

Features

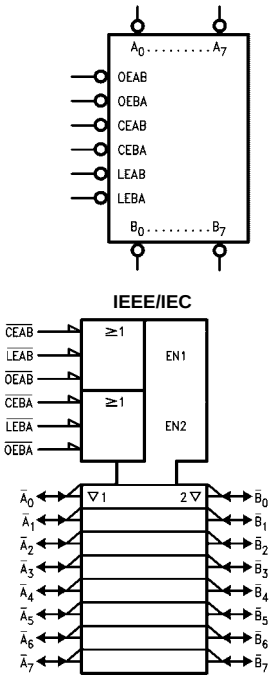
- 8-bit octal transceiver
- Back-to-back registers for storage
- Separate controls for data flow in each direction
- A outputs sink 24 mA, B outputs sink 64 mA

Ordering Code:

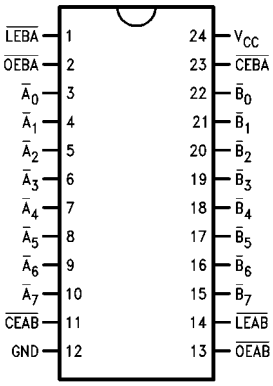
Order Number	Package Number	Package Description
74F544SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F544MSA	MSA24	24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F544SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L. HIGH/LOW	Input I_{IH}/I_{IL} Output I_{OH}/I_{OL}
$\overline{OEAB}$	A-to-B Output Enable Input (Active LOW)	1.0/1.0	20 µA/–0.6 mA
$\overline{OEBA}$	B-to-A Output Enable Input (Active LOW)	1.0/1.0	20 µA/–0.6 mA
$\overline{CEAB}$	A-to-B Enable Input (Active LOW)	1.0/2.0	20 µA/–1.2 mA
$\overline{CEBA}$	B-to-A Enable Input (Active LOW)	1.0/2.0	20 µA/–1.2 mA
$\overline{LEAB}$	A-to-B Latch Enable Input (Active LOW)	1.0/1.0	20 µA/–0.6 mA
$\overline{LEBA}$	B-to-A Latch Enable Input (Active LOW)	1.0/1.0	20 µA/–0.6 mA
$\overline{A}_0$–$\overline{A}_7$	A-to-B Data Inputs or	3.5/1.083	70 µA/–650 µA
	B-to-A 3-STATE Outputs	150/40(33.3)	–3 mA/24 mA (20 mA)
$\overline{B}_0$–$\overline{B}_7$	B-to-A Data Inputs or	3.5/1.083	70 µA/–650 µA
	A-to-B 3-STATE Outputs	600/106.6(80)	–12 mA/64 mA (48 mA)

Functional Description

The 74F544 contains two sets of eight D-type latches, with separate input and output controls for each set. For data flow from A to B, for example, the A-to-B Enable ($\overline{CEAB}$) input must be LOW in order to enter data from $\overline{A}_0$–$\overline{A}_7$ or take data from $\overline{B}_0$–$\overline{B}_7$, as indicated in the Data I/O Control Table. With $\overline{CEAB}$ LOW, a LOW signal on the A-to-B Latch Enable ($\overline{LEAB}$) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the $\overline{LEAB}$ signal puts the A latches in the storage mode and their outputs no longer change with the A inputs. With $\overline{CEAB}$ and $\overline{OEAB}$ both LOW, the 3-STATE B output buffers are active and reflect the data present at the output of the A latches. Control of data flow from B to A is similar, but using the $\overline{CEBA}$, $\overline{LEBA}$ and $\overline{OEBA}$ inputs.

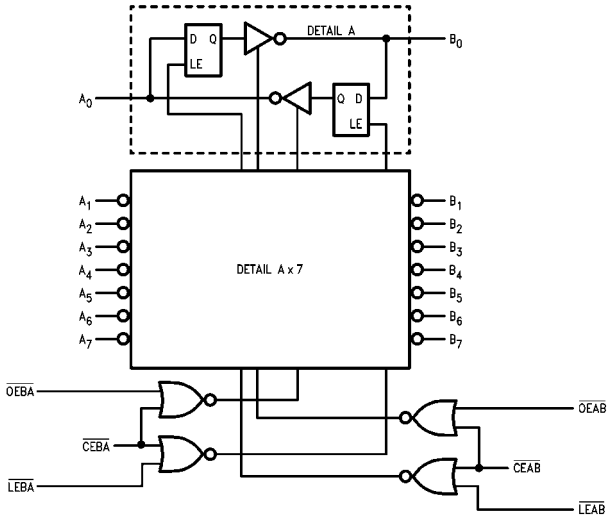
Data I/O Control Table

Inputs			Latch	Output
$\overline{CEAB}$	$\overline{LEAB}$	$\overline{OEAB}$	Status	Buffers
H	X	X	Latched	High Z
X	H	X	Latched	—
L	L	X	Transparent	—
X	X	H	—	High Z
L	X	L	—	Driving

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Note: A-to-B data flow shown; B-to-A flow control is the same, except using $\overline{CEBA}$, $\overline{LEBA}$ and $\overline{OEBA}$

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

Storage Temperature	−65°C to +150°C
Ambient Temperature under Bias	−55°C to +125°C
Junction Temperature under Bias	−55°C to +150°C
V_{CC} Pin Potential to Ground Pin	−0.5V to +7.0V
Input Voltage (Note 2)	−0.5V to +7.0V
Input Current (Note 2)	−30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with V_{CC} = 0V)	
Standard Output	−0.5V to V_{CC}
3-STATE Output	−0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature	0°C to +70°C
Supply Voltage	+4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter		Min	Typ	Max	Units	V_{CC}	Conditions
V_{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V_{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V_{CD}	Input Clamp Diode Voltage				−1.2	V	Min	I_{IN} = −18 mA, (except $\overline{A}_n$, $\overline{B}_n$)
V_{OH}	Output HIGH Voltage	10% V_{CC}	2.5			V	Min	I_{OH} = −1 mA ($\overline{A}_n$)
		10% V_{CC}	2.4					I_{OH} = −3 mA ($\overline{A}_n$, $\overline{B}_n$)
		10% V_{CC}	2.0					I_{OH} = −15 mA ($\overline{B}_n$)
		5% V_{CC}	2.7					I_{OH} = −1 mA ($\overline{A}_n$)
		5% V_{CC}	2.7					I_{OH} = −3 mA ($\overline{A}_n$, $\overline{B}_n$)
V_{OL}	Output LOW Voltage	10% V_{CC}			0.5	V	Min	I_{OL} = 24 mA ($\overline{A}_n$)
		10% V_{CC}			0.55			I_{OL} = 64 mA ($\overline{B}_n$)
I_{IH}	Input HIGH Current				20.0	µA	Max	V_{IN} = 2.7V (except $\overline{A}_n$, $\overline{B}_n$)
					5.0			
I_{BVI}	Input HIGH Current Breakdown Test				7.0	µA	Max	V_{IN} = 7.0V (except $\overline{A}_n$, $\overline{B}_n$)
I_{BVIT}	Input HIGH Current Breakdown (I/O)				0.5	mA	Max	V_{IN} = 5.5V ($\overline{A}_n$, $\overline{B}_n$)
I_{CEX}	Output HIGH Leakage Current				250	µA	Max	V_{OUT} = V_{CC} ($\overline{A}_n$, $\overline{B}_n$)
V_{ID}	Input Leakage Test		4.75			V	0.0	I_{ID} = 1.9 µA All Other Pins Grounded
I_{OD}	Output Leakage Circuit Current				3.75	µA	0.0	V_{IOD} = 150 mV All Other Pins Grounded
I_{IL}	Input LOW Current				−0.6	mA	Max	V_{IN} = 0.5V ($\overline{OEAB}$, $\overline{OEBA}$)
					−1.2			V_{IN} = 0.5V ($\overline{CEAB}$, $\overline{CEBA}$)
I_{IH} + I_{OZH}	Output Leakage Current				70	µA	Max	V_{OUT} = 2.7V ($\overline{A}_n$, $\overline{B}_n$)
I_{IL} + I_{OZL}	Output Leakage Current				−650	µA	Max	V_{OUT} = 0.5V ($\overline{A}_n$, $\overline{B}_n$)
I_{OS}	Output Short-Circuit Current		−60		−150	mA	Max	V_{OUT} = 0V ($\overline{A}_n$)
			−100		−225			V_{OUT} = 0V ($\overline{B}_n$)
I_{ZZ}	Bus Drainage Test				500	µA	0.0V	V_{OUT} = 5.25V ($\overline{A}_n$, $\overline{B}_n$)
I_{CCH}	Power Supply Current			70	105	mA	Max	V_O = HIGH
I_{CCL}	Power Supply Current			85	130	mA	Max	V_O = LOW
I_{CCZ}	Power Supply Current			83	125	mA	Max	V_O = HIGH Z

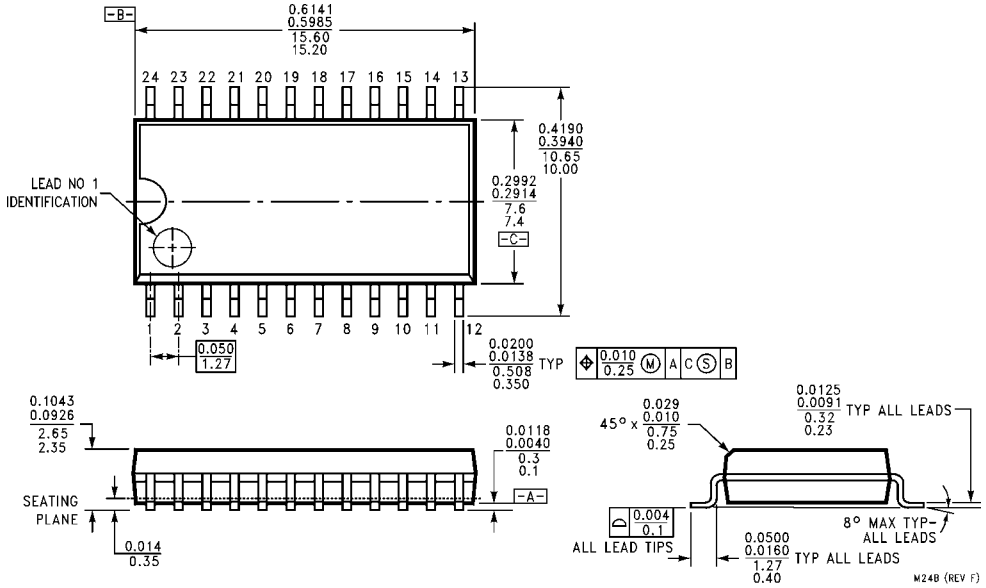
AC Electrical Characteristics

Symbol	Parameter	$T_A = +25°C$, $V_{CC} = +5.0V$, $C_L = 50$ pF			$T_A = -55°C$ to $+125°C$, $V_{CC} = +5.0V$, $C_L = 50$ pF		$T_A = 0°C$ to $+70°C$, $V_{CC} = +5.0V$, $C_L = 50$ pF		Units
		Min	Typ	Max	Min	Max	Min	Max	
t_{PLH}	Propagation Delay	3.0	7.0	9.5	3.0	12.0	3.0	10.5	ns
t_{PHL}	Transparent Mode	3.0	5.0	6.5	2.5	8.5	3.0	7.5	
	$\overline{A}_n$ to $\overline{B}_n$ or $\overline{B}_n$to $\overline{A}_n$								
t_{PLH}	Propagation Delay	6.0	10.0	13.0	6.0	18.0	6.0	14.5	ns
t_{PHL}	$\overline{LEBA}$ to $\overline{A}_n$	4.0	7.0	9.5	4.0	11.5	4.0	10.5	
t_{PLH}	Propagation Delay	6.0	10.0	13.0	6.0	18.0	6.0	14.5	ns
t_{PHL}	$\overline{LEAB}$ to $\overline{B}_n$	4.0	7.0	9.5	4.0	11.5	4.0	10.5	
t_{PZH}	Output Enable Time	3.0	7.0	9.0	3.0	11.0	3.0	10.0	ns
t_{PZL}	$\overline{OEBA}$ or $\overline{OEAB}$ to $\overline{A}_n$ or $\overline{B}_n$	4.0	7.5	10.5	4.0	13.0	4.0	12.0	
	$\overline{CEBA}$ or $\overline{CEAB}$ to $\overline{A}_n$ or $\overline{B}_n$								
t_{PHZ}	Output Disable Time	1.0	6.0	8.0	2.0	10.0	1.0	9.0	
t_{PLZ}	$\overline{OEBA}$ or $\overline{OEAB}$ to $\overline{A}_n$ or $\overline{B}_n$	2.5	5.5	10.5	2.0	9.5	2.5	11.5	
	$\overline{CEBA}$ or $\overline{CEAB}$ to $\overline{A}_n$ or $\overline{B}_n$								

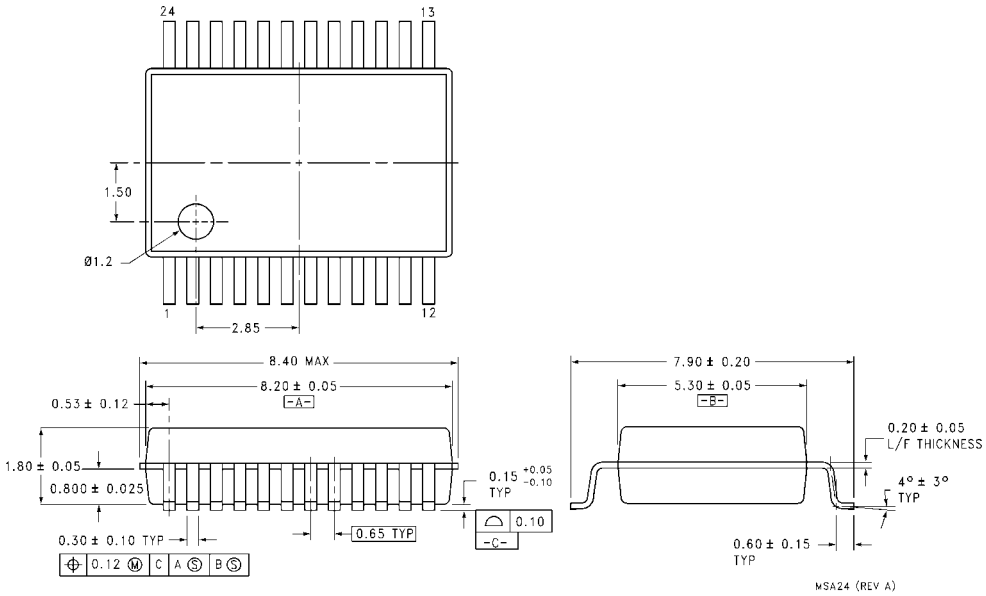
AC Operating Requirements

Symbol	Parameter	$T_A = +25°C$, $V_{CC} = +5.0V$		$T_A = -55°C$ to $+125°C$, $V_{CC} = +5.0V$		$T_A = 0°C$ to $+70°C$, $V_{CC} = +5.0V$		Units
		Min	Max	Min	Max	Min	Max	
$t_S(H)$	Setup Time, HIGH or LOW	3.0		3.0		3.0		ns
$t_S(L)$	$\overline{A}_n$ or $\overline{B}_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	3.0		3.0		3.0		
$t_H(H)$	Hold Time, HIGH or LOW	3.0		3.0		3.0		
$t_H(L)$	$\overline{A}_n$ or $\overline{B}_n$ to $\overline{LEBA}$ or $\overline{LEAB}$	3.0		3.0		3.0		
$t_W(L)$	Latch Enable, B to A Pulse Width, LOW	6.0		9.0		7.5		ns

Physical Dimensions inches (millimeters) unless otherwise noted

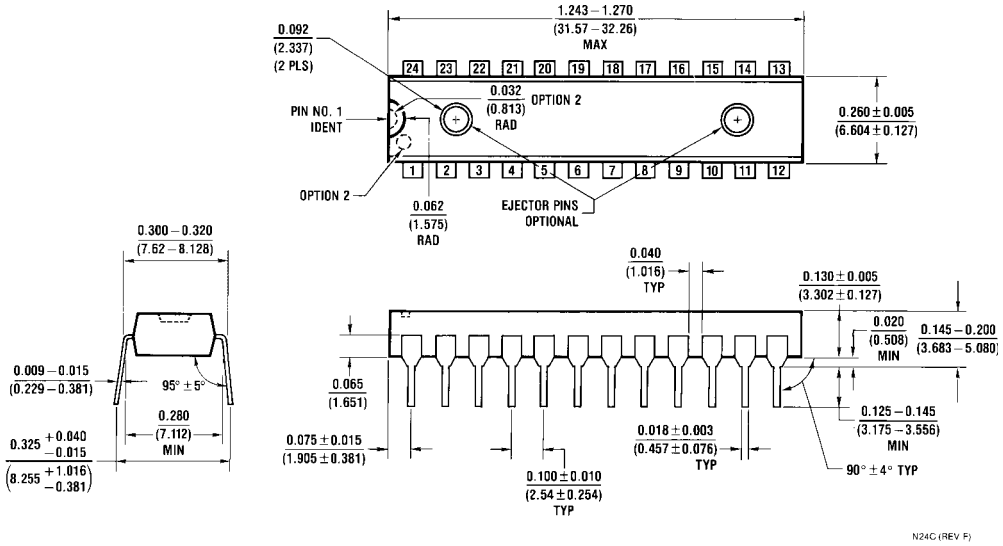


24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
Package Number M24B



24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
Package Number MSA24

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide
Package Number N24C

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